

INTERNATIONAL SEARCH REPORT

International Application No
/IL2004/000613

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G12B21/02 G01N21/65

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
IPC 7 G12B G01N G01J

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data, PAJ, INSPEC, COMPENDEX, EMBASE

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	SHUBEITA G T ET AL: "Scanning near-field optical microscopy using semiconductor nanocrystals as a local fluorescence and fluorescence resonance energy transfer source" JOURNAL OF MICROSCOPY BLACKWELL SCIENCE UK, vol. 210, no. 3, June 2003 (2003-06), pages 274-278, XP002300714 ISSN: 0022-2720 cited in the application figure 2 paragraph 'EXPERIMENTAL!'	1-14, 16-22, 29-33
Y A		15, 38 23-28, 34-37

☒ Further documents are listed in the continuation of box C.

☐ Patent family members are listed in annex.

* Special categories of cited documents:

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
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Date of the actual completion of the international search

14 October 2004

Date of mailing of the international search report

25/10/2004

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
Y	VICKERY S A ET AL: "Combining AFM and FRET for high resolution fluorescence microscopy" JOURNAL OF MICROSCOPY 2001 UNITED KINGDOM, vol. 202, no. 2, May 2001 (2001-05), pages 408-412, XP002300713 ISSN: 0022-2720 figure 2 paragraph 'EXPERIMENTAL!	15, 38
A		1-14, 16-37
X	OKAMOTO T ET AL: "NEAR-FIELD SCANNING OPTICAL MICROSCOPE USING A GOLD PARTICLE" JAPANESE JOURNAL OF APPLIED PHYSICS, PUBLICATION OFFICE JAPANESE JOURNAL OF APPLIED PHYSICS. TOKYO, JP, vol. 36, no. 2A, 1 February 1997 (1997-02-01), pages L166-L169, XP000732147 ISSN: 0021-4922 the whole document	1-13, 16-20, 22-27, 33-37
A		14, 15, 21, 28-32, 38
X	ANDERSON MARK S: "Locally enhanced Raman spectroscopy with an atomic force microscope" APPLIED PHYSICS LETTERS, AMERICAN INSTITUTE OF PHYSICS. NEW YORK, US, vol. 76, no. 21, 22 May 2000 (2000-05-22), pages 3130-3132, XP012025398 ISSN: 0003-6951 cited in the application the whole document	1-12, 16-23, 25-27, 32-34, 36, 37
A		13-15, 24, 28-31, 35-38
X	WESSEL J: "Surface-enhanced optical microscopy" JOURNAL OF THE OPTICAL SOCIETY OF AMERICA B (OPTICAL PHYSICS) USA, vol. 2, no. 9, September 1985 (1985-09), pages 1538-1541, XP002300715 ISSN: 0740-3224 figures 1,2 paragraphs 'INTRODUCTION!', 'SIGNAL!	1-12, 16-20, 23, 25, 34, 36
A		13-15, 21, 22, 24, 26-33, 35, 37, 38